

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/594,654	BUCK ET AL.	
Examiner	Art Unit	
SIN LEE	1722	

	SEARCHED				
Class	Subclass	Date	Examiner		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EIC TEXT/STRUCTURE SEARCHES	10/2/2011	SJL		